

# Electron-Beam-Induced Phase Transition in the Transmission Electron Microscope: The Case of $\text{VO}_2(\text{B})$

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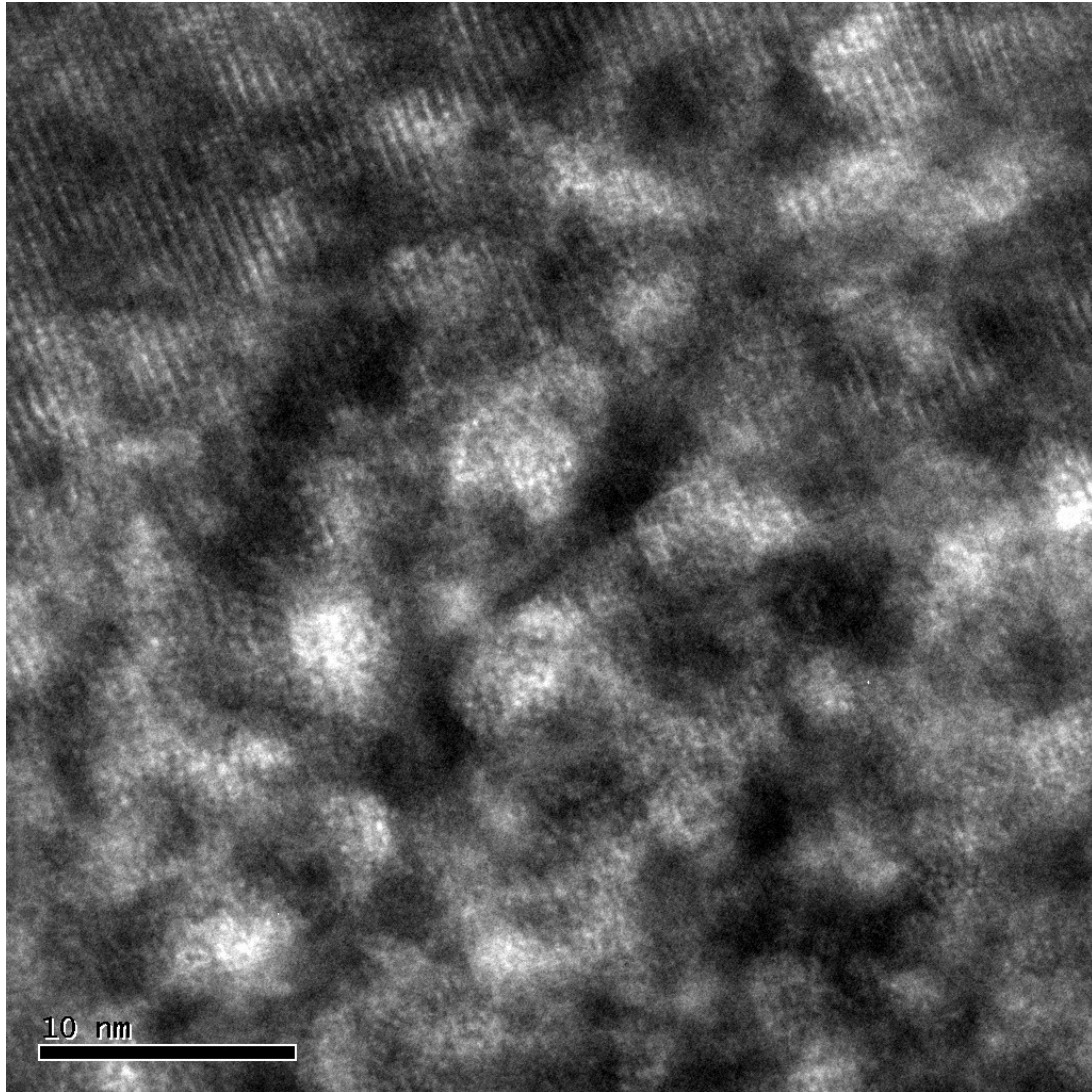
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## **Supplementary Information**

### **List of contents.**

**Figure S1 | HRTEM image at the boundary of the  $\text{VO}_2(\text{B})/\text{VO}_2(\text{M1})$  interface of**

**Fig. 3(c).**



**Figure S1 | HRTEM image at the boundary of the VO<sub>2</sub>(B)/VO<sub>2</sub>(M1) interface of Fig. 3(c).** We have examined our samples by Transmission electron microscope (TEM) to confirm the sample structure at the boundary of the VO<sub>2</sub>(B)/VO<sub>2</sub>(M1) interface. The lattice image of VO<sub>2</sub>(B) is depicted at the top and the vague image of the VO<sub>2</sub>(M1) is shown at the bottom.

